February 2001

FDN308P

SEMICONDUCTOR IM

P-Channel 2.5V Specified PowerTrench[®] MOSFET

General Description

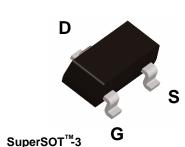
This P-Channel 2.5V specified MOSFET uses a rugged gate version of Fairchild's advanced PowerTrench process. It has been optimized for power management applications with a wide range of gate drive voltage (2.5V - 12V).

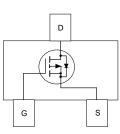
Applications

- Power management
- Load switch
- Battery protection

Features

- -20 V, -1.5 A. $R_{DS(ON)} = 125 \text{ m}\Omega @ V_{GS} = -4.5 \text{ V}$ $R_{DS(ON)} = 190 \text{ m}\Omega @ V_{GS} = -2.5 \text{ V}$
- Fast switching speed
- High performance trench technology for extremely low $R_{\text{DS}(\text{ON})}$
- SuperSOTTM -3 provides low R_{DS(ON)} and 30% higher power handling capability than SOT23 in the same footprint





Absolute Maximum Ratings T_{A=25°C unless otherwise noted}

Symbol	Parameter			Ratings	Units	
V _{DSS}	Drain-Sourc	e Voltage	-20	V		
V _{GSS}	Gate-Source	e Voltage	±12			
ID	Drain Curre	nt – Continuous	(Note 1a)	-1.5	A	
	– Pulsed			-10		
P _D	Maximum Power Dissipation		(Note 1a)	0.5	W	
			(Note 1b)	0.46		
T _J , T _{STG}	Operating a	nd Storage Junction Te	-55 to +150			
Therma	I Charact	teristics				
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1a)		250	°C/W		
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case (No		ase (Note 1)	75	°C/W	
Packag	e Marking	g and Ordering	Information			
Device Marking		Device	Reel Size	Tape width	Quantity	
308		FDN308P	7"	8mm	3000 units	

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Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$	-20			V
<u>ΔBVdss</u> ΔTj	Breakdown Voltage Temperature Coefficient	$I_D = -250 \ \mu\text{A}, \text{Referenced to } 25^{\circ}\text{C}$		-13		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current $V_{DS} = -16 V$, $V_{GS} = 0 V$				-1	μA
I _{GSSF}	Gate-Body Leakage, Forward	$V_{GS} = 12 \text{ V}, \qquad V_{DS} = 0 \text{ V}$			100	nA
I _{GSSR}	Gate-Body Leakage, Reverse	$V_{GS} = -12 \text{ V} \qquad V_{DS} = 0 \text{ V}$			-100	nA
On Char	acteristics (Note 2)	·				
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \ \mu A$	-0.6	-1.0	-1.5	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	$I_D = -250 \ \mu\text{A}, \text{Referenced to } 25^{\circ}\text{C}$		3		mV/°C
R _{DS(on)}	Static Drain–Source	$V_{GS} = -4.5 \text{ V}, I_D = -1.5 \text{ A}$		86	125	mΩ
	On-Resistance	$V_{GS} = -2.5 \text{ V}, I_D = -1.3 \text{ A}$		136	190	
		$V_{GS} = -4.5 \text{ V}, I_D = -1.5 \text{ A} \text{ T}_J = 125^{\circ}\text{C}$		114	178	
D(on)	On–State Drain Current	$V_{GS} = -4.5 \text{ V}, V_{DS} = -5 \text{ V}$	-5			A
g fs	Forward Transconductance	$V_{DS} = -5 V$, $I_D = -1.5 A$		12		S
Dynamic	Characteristics				1	
C _{iss}	Input Capacitance	$V_{DS} = -10 \text{ V}, \qquad V_{GS} = 0 \text{ V},$		341		pF
Coss	Output Capacitance	f = 1.0 MHz		83		pF
Crss	Reverse Transfer Capacitance			43		pF
t _{d(on)}	Turn–On Delay Time	$V_{DD} = -10 \ V, \qquad I_D = -1 \ A,$		8	16	ns
t _r	Turn–On Rise Time	$V_{\rm GS} = -4.5 \text{ V}, \qquad R_{\rm GEN} = 6 \ \Omega$		10	20	ns
$t_{d(off)}$	Turn–Off Delay Time			12	22	ns
t _f	Turn–Off Fall Time			8	16	ns
Qg	Total Gate Charge	$V_{DS} = -10V$, $I_D = -1.5 A$,		3.8	5.4	nC
Q _{gs}	Gate-Source Charge	$V_{GS} = -4.5 V$		0.8		nC
Q _{gd}	Gate-Drain Charge	1		1.0		nC
Drain-S	ource Diode Characteristics	and Maximum Ratings		•		
Is	Maximum Continuous Drain–Source				-0.42	А
V _{SD}	Drain–Source Diode Forward Voltage	$V_{GS} = 0 V, I_{S} = -0.42$ (Note 2)		-0.7	-1.2	V

Notes:

1. R_{0JA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.

a) 250°C/W when mounted on a 0.02 in² pad of 2 oz. copper.

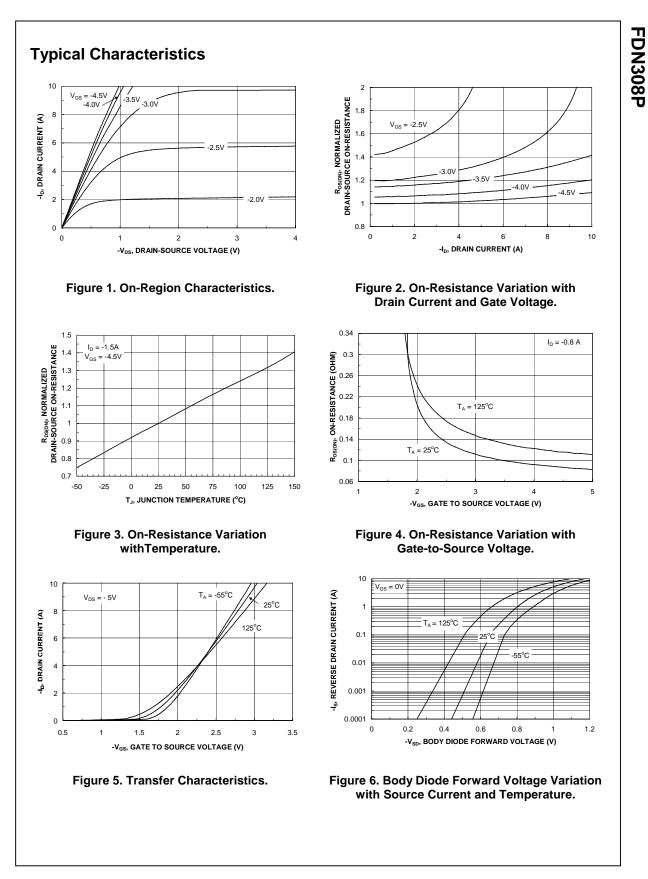
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b) 270°C/W when mounted on a minimum pad.

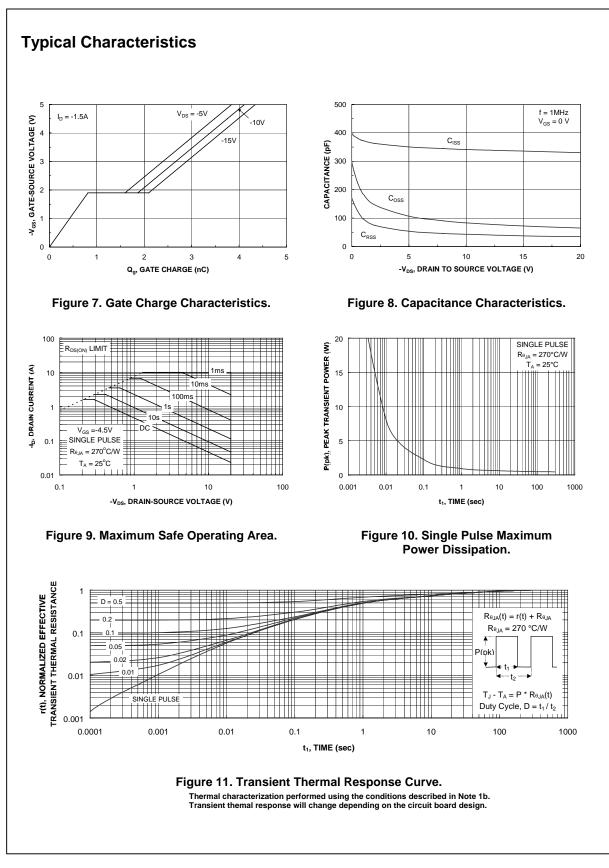
6 Scale 1 : 1 on letter size paper

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2. Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 2.0%



FDN308P Rev B(W)



FDN308P Rev B(W)

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